E.J. Lattice Semiconductor Corporation - <u>LFE5U-85F-8BG381C Datasheet</u>



Welcome to E-XFL.COM

Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	21000
Number of Logic Elements/Cells	84000
Total RAM Bits	3833856
Number of I/O	205
Number of Gates	-
Voltage - Supply	1.045V ~ 1.155V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	381-FBGA
Supplier Device Package	381-CABGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe5u-85f-8bg381c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



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Acronyms in This Document

A list of acronyms used in this document.

ALUArithmetic Logic UnitBGABall Grid ArrayCDRClock and Data RecoveryCRCCycle Redundancy CodeDCCDynamic Clock ControlDCSDynamic Clock SelectDDRDouble Data RateDLLDelay-Locked LoopsDSPDigital Signal ProcessingEBREmbedded Block RAMECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Transistor-Transistor LogicLVTLLow Voltage Transistor-Transistor LogicLVTLPripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSERDESSerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access PortTDMTime D	Acronym	Definition
CDRClock and Data RecoveryCRCCycle Redundancy CodeDCCDynamic Clock ControlDCSDynamic Clock SelectDDRDouble Data RateDLLDelay-Locked LoopsDSPDigital Signal ProcessingEBREmbedded Block RAMECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Transistor-Transistor LogicLVTLLow Voltage Positive Emitter Coupled LogicLVTLLow Voltage Transistor-Transistor LogicLVTLPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	ALU	Arithmetic Logic Unit
CRCCycle Redundancy CodeDCCDynamic Clock ControlDCSDynamic Clock SelectDDRDouble Data RateDLLDelay-Locked LoopsDSPDigital Signal ProcessingEBREmbedded Block RAMECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	BGA	Ball Grid Array
DCCDynamic Clock ControlDCSDynamic Clock SelectDDRDouble Data RateDLLDelay-Locked LoopsDSPDigital Signal ProcessingEBREmbedded Block RAMECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	CDR	Clock and Data Recovery
DCSDynamic Clock SelectDDRDouble Data RateDLLDelay-Locked LoopsDSPDigital Signal ProcessingEBREmbedded Block RAMECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICSeralizer/DeserializerSERDESSerializer/DeserializerSELUSingle Event UpsetSERDESSerializer/DeserializerSELUSingle Port RAMSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	CRC	Cycle Redundancy Code
DDRDouble Data RateDLLDelay-Locked LoopsDSPDigital Signal ProcessingEBREmbedded Block RAMECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICSERDES Client InterfaceSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	DCC	Dynamic Clock Control
DLLDelay-Locked LoopsDSPDigital Signal ProcessingEBREmbedded Block RAMECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICSERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	DCS	Dynamic Clock Select
DSPDigital Signal ProcessingEBREmbedded Block RAMECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICSERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	DDR	Double Data Rate
EBREmbedded Block RAMECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable Functional UnitPICSERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	DLL	Delay-Locked Loops
ECLKEdge ClockFFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTLLow Voltage Transistor-Transistor LogicLVTTLLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	DSP	Digital Signal Processing
FFTFast Fourier TransformsFIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	EBR	Embedded Block RAM
FIFOFirst In First OutFIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable Functional UnitPICSERDES Client InterfaceSCISERDES Client InterfaceSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	ECLK	Edge Clock
FIRFinite Impulse ResponseLVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable Functional UnitPICSERDES Client InterfaceSCISERDES Client InterfaceSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	FFT	Fast Fourier Transforms
LVCMOSLow-Voltage Complementary Metal Oxide SemiconductorLVDSLow-Voltage Differential SignalingLVPECLLow Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	FIFO	First In First Out
LVDSLow-Voltage Differential SignalingLVPECLLow-Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	FIR	Finite Impulse Response
LVPECLLow Voltage Positive Emitter Coupled LogicLVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	LVCMOS	Low-Voltage Complementary Metal Oxide Semiconductor
LVTTLLow Voltage Transistor-Transistor LogicLUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	LVDS	Low-Voltage Differential Signaling
LUTLook Up TableMLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	LVPECL	Low Voltage Positive Emitter Coupled Logic
MLVDSMultipoint Low-Voltage Differential SignalingPCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	LVTTL	Low Voltage Transistor-Transistor Logic
PCIPeripheral Component InterconnectPCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	LUT	Look Up Table
PCSPhysical Coding SublayerPCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	MLVDS	Multipoint Low-Voltage Differential Signaling
PCLKPrimary ClockPDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	PCI	Peripheral Component Interconnect
PDPRPseudo Dual Port RAMPFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	PCS	Physical Coding Sublayer
PFUProgrammable Functional UnitPICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	PCLK	Primary Clock
PICProgrammable I/O CellsPLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	PDPR	Pseudo Dual Port RAM
PLLPhase-Locked LoopsPORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	PFU	Programmable Functional Unit
PORPower On ResetSCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	PIC	Programmable I/O Cells
SCISERDES Client InterfaceSERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	PLL	Phase-Locked Loops
SERDESSerializer/DeserializerSEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	POR	Power On Reset
SEUSingle Event UpsetSLVSScalable Low-Voltage SignalingSPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	SCI	SERDES Client Interface
SLVS Scalable Low-Voltage Signaling SPI Serial Peripheral Interface SPR Single Port RAM SRAM Static Random-Access Memory TAP Test Access Port	SERDES	Serializer/Deserializer
SPISerial Peripheral InterfaceSPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	SEU	Single Event Upset
SPRSingle Port RAMSRAMStatic Random-Access MemoryTAPTest Access Port	SLVS	Scalable Low-Voltage Signaling
SRAM Static Random-Access Memory TAP Test Access Port	SPI	Serial Peripheral Interface
TAP Test Access Port	SPR	Single Port RAM
	SRAM	Static Random-Access Memory
TDM Time Division Multiplexing	ТАР	Test Access Port
	TDM	Time Division Multiplexing

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2.8.6. Memory Core Reset

The memory array in the EBR utilizes latches at the A and B output ports. These latches can be reset asynchronously or synchronously. RSTA and RSTB are local signals, which reset the output latches associated with Port A and Port B, respectively. The Global Reset (GSRN) signal can reset both ports. The output data latches and associated resets for both ports are as shown in Figure 2.12.

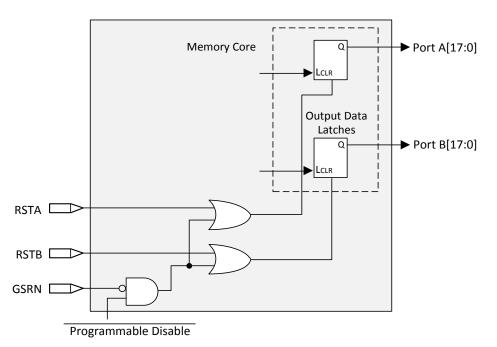


Figure 2.12. Memory Core Reset

For further information on the sysMEM EBR block, see the list of technical documentation in Supplemental Information section on page 102.

2.9. sysDSP[™] Slice

The ECP5/ECP5-5G family provides an enhanced sysDSP architecture, making it ideally suited for low-cost, high-performance Digital Signal Processing (DSP) applications. Typical functions used in these applications are Finite Impulse Response (FIR) filters, Fast Fourier Transforms (FFT) functions, Correlators, Reed-Solomon/Turbo/Convolution encoders and decoders. These complex signal processing functions use similar building blocks such as multiply-adders and multiply-accumulators.

2.9.1. sysDSP Slice Approach Compared to General DSP

Conventional general-purpose DSP chips typically contain one to four (Multiply and Accumulate) MAC units with fixed data-width multipliers; this leads to limited parallelism and limited throughput. Their throughput is increased by higher clock speeds. In the ECP5/ECP5-5G device family, there are many DSP slices that can be used to support different data widths. This allows designers to use highly parallel implementations of DSP functions. Designers can optimize DSP performance vs. area by choosing appropriate levels of parallelism. Figure 2.13 compares the fully serial implementation to the mixed parallel and serial implementation.

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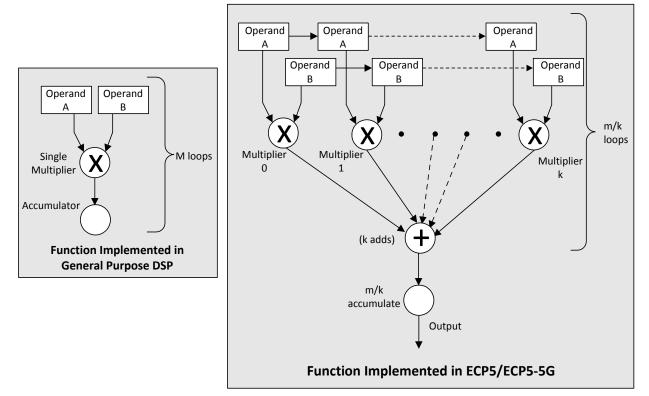


Figure 2.13. Comparison of General DSP and ECP5/ECP5-5G Approaches

2.9.2. sysDSP Slice Architecture Features

The ECP5/ECP5-5G sysDSP Slice has been significantly enhanced to provide functions needed for advanced processing applications. These enhancements provide improved flexibility and resource utilization.

The ECP5/ECP5-5G sysDSP Slice supports many functions that include the following:

- Symmetry support. The primary target application is wireless. 1D Symmetry is useful for many applications that use FIR filters when their coefficients have symmetry or asymmetry characteristics. The main motivation for using 1D symmetry is cost/size optimization. The expected size reduction is up to 2x.
 - Odd mode Filter with Odd number of taps
 - Even mode Filter with Even number of taps
 - Two dimensional (2D) symmetry mode supports 2D filters for mainly video applications
- Dual-multiplier architecture. Lower accumulator overhead to half and the latency to half compared to single multiplier architecture
- Fully cascadable DSP across slices. Support for symmetric, asymmetric and non-symmetric filters.
- Multiply (one 18x36, two 18x18 or four 9x9 Multiplies per Slice)
- Multiply (36x36 by cascading across two sysDSP slices)
- Multiply Accumulate (supports one 18x36 multiplier result accumulation or two 18x18 multiplier result accumulation)
- Two Multiplies feeding one Accumulate per cycle for increased processing with lower latency (two 18x18 Multiplies feed into an accumulator that can accumulate up to 52 bits)
- Pipeline registers
- 1D Symmetry support. The coefficients of FIR filters have symmetry or negative symmetry characteristics.
 - Odd mode Filter with Odd number of taps
 - Even mode Filter with Even number of taps
- 2D Symmetry support. The coefficients of 2D FIR filters have symmetry or negative symmetry characteristics.
 - 3*3 and 3*5 Internal DSP Slice support

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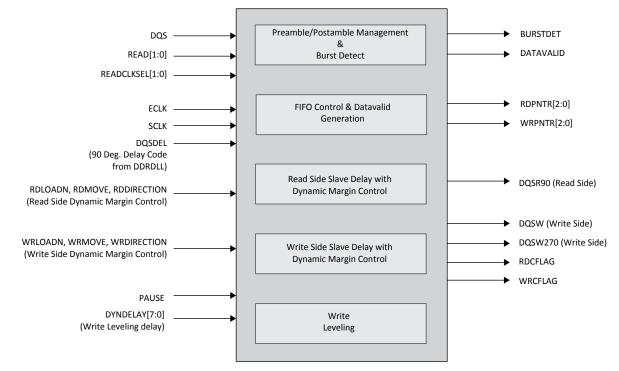


Figure 2.24. DQS Control and Delay Block (DQSBUF)

Table 2.11	DQSBUF	Port List	Description
------------	--------	------------------	-------------

Name	Туре	Description
DQS	Input	DDR memory DQS strobe
READ[1:0]	Input	Read Input from DDR Controller
READCLKSEL[1:0]	Input	Read pulse selection
SCLK	Input	Slow System Clock
ECLK	Input	High Speed Edge Clock (same frequency as DDR memory)
DQSDEL	Input	90° Delay Code from DDRDLL
RDLOADN, RDMOVE, RDDIRECTION	Input	Dynamic Margin Control ports for Read delay
WRLOADN, WRMOVE, WRDIRECTION	Input	Dynamic Margin Control ports for Write delay
PAUSE	Input	Used by DDR Controller to Pause write side signals during DDRDLL Code update or Write Leveling
DYNDELAY[7:0]	Input	Dynamic Write Leveling Delay Control
DQSR90	Output	90° delay DQS used for Read
DQSW270	Output	90° delay clock used for DQ Write
DQSW	Output	Clock used for DQS Write
RDPNTR[2:0]	Output	Read Pointer for IFIFO module
WRPNTR[2:0]	Output	Write Pointer for IFIFO module
DATAVALID	Output	Signal indicating start of valid data
BURSTDET	Output	Burst Detect indicator
RDFLAG	Output	Read Dynamic Margin Control output to indicate max value
WRFLAG	Output	Write Dynamic Margin Control output to indicate max value

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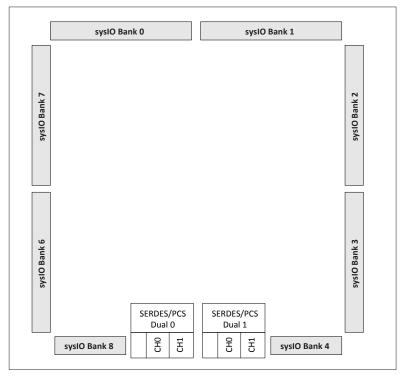


Figure 2.27. SERDES/PCS Duals (LFE5UM/LFE5UM5G-85)

Standard	Data Rate (Mb/s)	Number of General/Link Width	Encoding Style
PCI Express 1.1 and 2.0	2500	x1, x2, x4	8b10b
2.02	5000 ²	x1, x2	8b10b
Gigabit Ethernet	1250	x1	8b10b
COMU	1250	x1	8b10b
SGMII	2500	x1	8b10b
XAUI	3125	x4	8b10b
CPRI-1 CPRI-2 CPRI-3 CPRI-4 CPRI-5	614.4 1228.8 2457.6 3072.0 4915.2 ²	x1	8b10b
SD-SDI (259M, 344M) 1	270	x1	NRZI/Scrambled
HD-SDI (292M)	1483.5 1485	x1	NRZI/Scrambled
3G-SDI (424M)	2967 2970	x1	NRZI/Scrambled
	5000	_	_
JESD204A/B	3125	x1	8b/10b

Notes:

1. For SD-SDI rate, the SERDES is bypassed and SERDES input signals are directly connected to the FPGA routing.

2. For ECP5-5G family devices only.



Table 3.10. ECP5-5G

Symbol	Description	Тур	Max	Unit	
Standby (Power Down)					
I _{CCA-SB}	V _{CCA} Power Supply Current (Per Channel)	4	9.5	mA	
I _{CCHRX-SB} ⁴	V _{CCHRX} , Input Buffer Current (Per Channel)	_	0.1	mA	
I _{CCHTX-SB}	V _{CCHTX} , Output Buffer Current (Per Channel)	_	0.9	mA	
Operating (Da	ata Rate = 5 Gb/s)				
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	58	67	mA	
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA	
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA	
Operating (D	ata Rate = 3.2 Gb/s)				
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	48	57	mA	
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA	
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA	
Operating (Da	ata Rate = 2.5 Gb/s)				
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	44	53	mA	
I _{CCHRX-OP} ⁵	V _{CCHRx} , Input Buffer Current (Per Channel)	0.4	0.5	mA	
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA	
Operating (Da	ata Rate = 1.25 Gb/s)				
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	36	46	mA	
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA	
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA	
Operating (D	ata Rate = 270 Mb/s)				
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	30	40	mA	
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA	
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	8	10	mA	

Notes:

1. Rx Equalization enabled, Tx De-emphasis (pre-cursor and post-cursor) disabled

2. Per Channel current is calculated with both channels on in a Dual, and divide current by two. If only one channel is on, current will be higher.

3. To calculate with Tx De-emphasis enabled, use the Diamond Power Calculator tool.

4. For ICCHRX-SB, during Standby, input termination on Rx are disabled.

5. For ICCHRX-OP, during operational, the max specified when external AC coupling is used. If externally DC coupled, the power is based on current pulled down by external driver when the input is driven to LOW.



3.14.4. LVDS25E

The top and bottom sides of ECP5/ECP5-5G devices support LVDS outputs via emulated complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The scheme shown in Figure 3.1 is one possible solution for point-to-point signals.

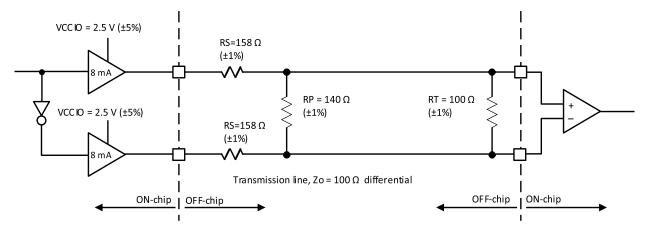


Figure 3.1. LVDS25E Output Termination Example

Table 3.14. LVDS25E DC Conditions

Parameter	Description	Typical	Unit
V _{CCIO}	Output Driver Supply (±5%)	2.50	V
Z _{OUT}	Driver Impedance	20	Ω
Rs	Driver Series Resistor (±1%)	158	Ω
R _P	Driver Parallel Resistor (±1%)	140	Ω
R _T	Receiver Termination (±1%)	100	Ω
V _{OH}	Output High Voltage	1.43	V
V _{OL}	Output Low Voltage	1.07	V
V _{OD}	Output Differential Voltage	0.35	V
V _{CM}	Output Common Mode Voltage	1.25	V
ZBACK	Back Impedance	100.5	Ω
I _{DC}	DC Output Current	6.03	mA

Note: For input buffer, see LVDS Table 3.13 on page 55.



3.14.8. SLVS

Scalable Low-Voltage Signaling (SLVS) is based on a point-to-point signaling method defined in the JEDEC JESD8-13 (SLVS-400) standard. This standard evolved from the traditional LVDS standard and relies on the advantage of its use of smaller voltage swings and a lower common-mode voltage. The 200 mV (400 mV p-p) SLVS swing contributes to a reduction in power.

The ECP5/ECP5-5G devices can receive differential input up to 800 Mb/s with its LVDS input buffer. This LVDS input buffer is used to meet the SLVS input standard specified by the JEDEC standard. The SLVS output parameters are compared to ECP5/ECP5-5G LVDS input parameters, as listed in Table 3.18.

Table 3.18. Input to SLVS

Parameter	ECP5/ECP5-5G LVDS Input	SLVS Output	Unit
Vcm (min)	50	150	mV
Vcm (max)	2350	250	mV
Differential Voltage (min)	100	140	mV
Differential Voltage (max)	-	270	mV

ECP5/ECP5-5G does not support SLVS output. However, SLVS output can be created using ECP5/ECP5-5G LVDS outputs by level shift to meet the low Vcm/Vod levels required by SLVS. Figure 3.5 shows how the LVDS output can be shifted external to meet SLVS levels.

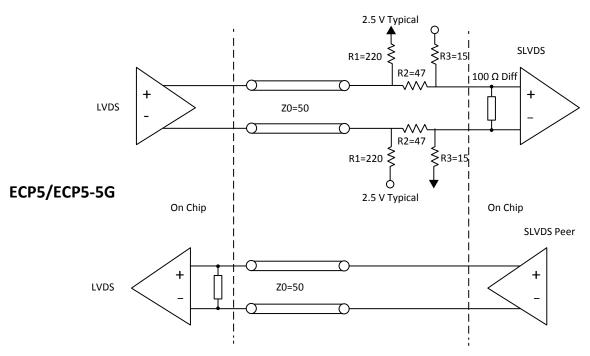


Figure 3.5. SLVS Interface

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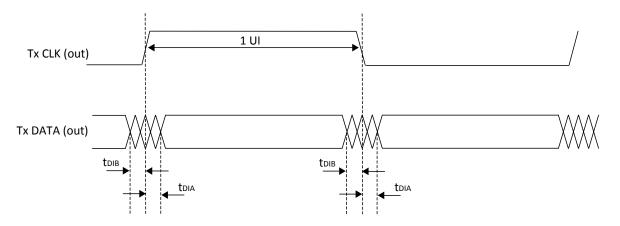
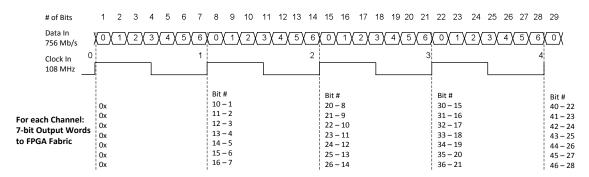


Figure 3.9. Transmit TX.CLK.Aligned Waveforms

Receiver – Shown for one LVDS Channel



Transmitter - Shown for one LVDS Channel

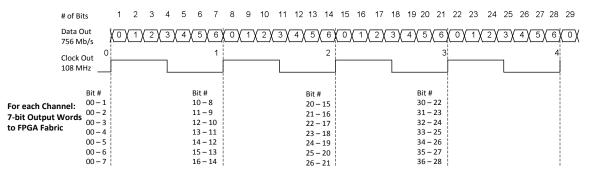


Figure 3.10. DDRX71 Video Timing Waveforms

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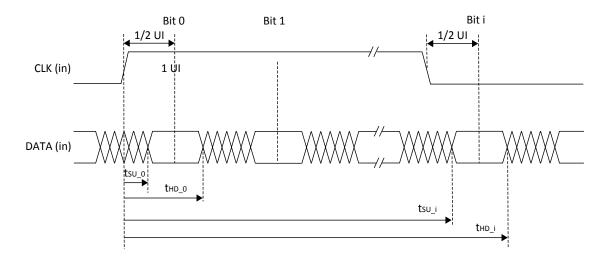


Figure 3.11. Receiver DDRX71_RX Waveforms

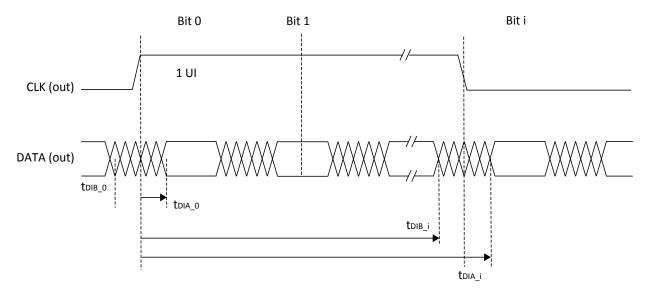


Figure 3.12. Transmitter DDRX71_TX Waveforms



3.19. sysCLOCK PLL Timing

Over recommended operating conditions.

Parameter	Descriptions	Conditions	Min	Max	Units
f _{IN}	Input Clock Frequency (CLKI, CLKFB)	_	8	400	MHz
f _{out}	Output Clock Frequency (CLKOP, CLKOS)	—	3.125	400	MHz
f _{vco}	PLL VCO Frequency	—	400	800	MHz
$f_{\text{PFD}}{}^3$	Phase Detector Input Frequency	_	10	400	MHz
AC Characteris	itics				
t _{DT}	Output Clock Duty Cycle	_	45	55	%
t _{PH4}	Output Phase Accuracy	_	-5	5	%
		f _{o∪T} ≥ 100 MHz	_	100	ps p-p
	Output Clock Period Jitter	f _{о∪т} < 100 MHz	_	0.025	UIPP
		f _{o∪T} ≥ 100 MHz	_	200	ps p-p
t _{opjit} 1	Output Clock Cycle-to-Cycle Jitter	f _{о∪т} < 100 MHz	_	0.050	UIPP
	Output Clock Phase Jitter	f _{PFD} ≥ 100 MHz	_	200	ps p-p
		f _{PFD} < 100 MHz	_	0.011	UIPP
t _{spo}	Static Phase Offset	Divider ratio = integer	_	400	ps p-p
t _w	Output Clock Pulse Width	At 90% or 10%	0.9	_	ns
t _{LOCK} ²	PLL Lock-in Time	_	_	15	ms
t _{UNLOCK}	PLL Unlock Time	_	_	50	ns
_		f _{PFD} ≥ 20 MHz	_	1,000	ps p-p
t _{IPJIT}	Input Clock Period Jitter	f _{PFD} < 20 MHz	_	0.02	UIPP
t _{HI}	Input Clock High Time	90% to 90%	0.5	_	ns
t _{LO}	Input Clock Low Time	10% to 10%	0.5	_	ns
t _{RST}	RST/ Pulse Width	_	1	_	ms
t _{rstrec}	RST Recovery Time	_	1	-	ns
t _{load_reg}	Min Pulse for CIB_LOAD_REG	_	10	_	ns
t _{ROTATE-SETUP}	Min time for CIB dynamic phase controls to be stable fore CIB_ROTATE	_	5	_	ns
t _{rotate-wd}	Min pulse width for CIB_ROTATE to maintain "0" or	_	4	-	VCO cycles

Notes:

1. Jitter sample is taken over 10,000 samples for Periodic jitter, and 2,000 samples for Cycle-to-Cycle jitter of the primary PLL output with clean reference clock with no additional I/O toggling.

2. Output clock is valid after t_{LOCK} for PLL reset and dynamic delay adjustment.

3. Period jitter and cycle-to-cycle jitter numbers are guaranteed for $f_{PFD} > 10$ MHz. For $f_{PFD} < 10$ MHz, the jitter numbers may not be met in certain conditions.



3.24. SERDES External Reference Clock

The external reference clock selection and its interface are a critical part of system applications for this product. Table 3.29 specifies reference clock requirements, over the full range of operating conditions.

Symbol	Description	Min	Тур	Max	Unit	
F _{REF}	Frequency range	50	—	320	MHz	
F _{REF-PPM}	Frequency tolerance ¹	-1000	—	1000	ppm	
V _{REF-IN-SE}	Input swing, single-ended clock ^{2, 4}	200	—	V _{CCAUXA}	тV, р-р	
V _{REF-IN-DIFF}	Input swing, differential clock	200	– 2*V _{CCAUXA}		mV, p-p differential	
V _{REF-IN}	Input levels	0	—	V _{CCAUXA} + 0.4	V	
D _{REF}	Duty cycle ³	40	—	60	%	
T _{REF-R}	Rise time (20% to 80%)	200	500	1000	ps	
T _{REF-F}	Fall time (80% to 20%)	200	500	1000	ps	
Z _{REF-IN-TERM-DIFF}	Differential input termination	-30%	100/HiZ	+30%	Ω	
C _{REF-IN-CAP}	Input capacitance	_	_	7	pF	

Table 3.29. External Reference Clock Specification (refclkp/refclkn)

Notes:

1. Depending on the application, the PLL_LOL_SET and CDR_LOL_SET control registers may be adjusted for other tolerance values as described in ECP5 and ECP5-5G SERDES/PCS Usage Guide (TN1261).

- 2. The signal swing for a single-ended input clock must be as large as the p-p differential swing of a differential input clock to get the same gain at the input receiver. With single-ended clock, a reference voltage needs to be externally connected to CLKREFN pin, and the input voltage needs to be swung around this reference voltage.
- 3. Measured at 50% amplitude.
- 4. Single-ended clocking is achieved by applying a reference voltage V_{REF} on REFCLKN input, with the clock applied to REFCLKP input pin. V_{REF} should be set to mid-point of the REFCLKP voltage swing.

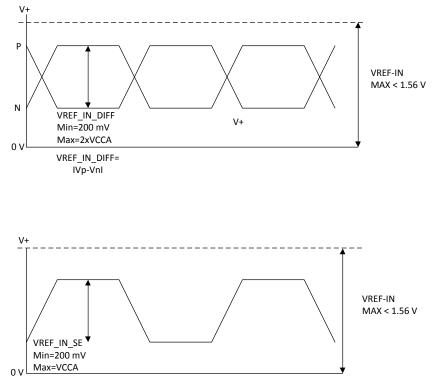


Figure 3.14. SERDES External Reference Clock Waveforms

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3.25.2. PCIe (5 Gb/s) – Preliminary AC and DC Characteristics

Over recommended operating conditions.

Table 3.31. PCIe (5 Gb/s)

Symbol	Description	Test Conditions	Min	Тур	Max	Unit
Transmit ¹						
UI	Unit Interval	—	199.94	200	200.06	ps
B _{WTX-PKG-PLL2}	Tx PLL bandwidth corresponding to PKGTX-PLL2	_	5	-	16	MHz
P _{KGTX-PLL2}	Tx PLL Peaking	—	-	—	1	dB
V _{TX-DIFF-PP}	Differential p-p Tx voltage swing	—	0.8	_	1.2	V, p-p
V _{TX-DIFF-PP-LOW}	Low power differential p-p Tx voltage swing	_	0.4	_	1.2	V, p-p
V _{TX-DE-RATIO-3.5dB}	Tx de-emphasis level ratio at 3.5dB	—	3	—	4	dB
V _{TX-DE-RATIO-6dB}	Tx de-emphasis level ratio at 6dB	—	5.5	—	6.5	dB
T _{MIN-PULSE}	Instantaneous lone pulse width	_		—	_	UI
T _{TX-RISE-FALL}	Transmitter rise and fall time	_		—	_	UI
T _{TX-EYE}	Transmitter Eye, including all jitter sources	_	0.75	_	_	UI
T _{TX-DJ}	Tx deterministic jitter > 1.5 MHz	_	_	—	0.15	UI
T _{TX-RJ}	Tx RMS jitter < 1.5 MHz	_	_	_	3	ps, RMS
T _{RF-MISMATCH}	Tx rise/fall time mismatch	—	_	—		UI
D	Tx Differential Return Loss, including	50 MHz < freq < 1.25 GHz	10	_	_	dB
R _{LTX-DIFF}	package and silicon	1.25 GHz < freq < 2.5 GHz	8	_	_	dB
R _{LTX-CM}	Tx Common Mode Return Loss, including package and silicon	50 MHz < freq < 2.5 GHz	6	_	_	dB
Z _{TX-DIFF-DC}	DC differential Impedance	_	-	_	120	Ω
V _{TX-CM-AC-PP}	Tx AC peak common mode voltage, peak-peak	-	-	-		mV, p-p
I _{TX-SHORT}	Transmitter short-circuit current	—	_	—	90	mA
V _{TX-DC-CM}	Transmitter DC common-mode voltage	_	0	-	1.2	V
V _{TX-IDLE-DIFF-DC}	Electrical Idle Output DC voltage	—	0	—	5	mV
V _{TX-IDLE-DIFF-AC-p}	Electrical Idle Differential Output peak voltage	-	_	-		mV
V _{TX-RCV-DETECT}	Voltage change allowed during Receiver Detect	-	_	-	600	mV
T _{TX-IDLE-MIN}	Min. time in Electrical Idle	—	20	_	_	ns
T _{TX-IDLE-SET-TO-IDLE}	Max. time from El Order Set to valid Electrical Idle	_	_	-	8	ns
T _{TX-IDLE-TO-DIFF-DATA}	Max. time from Electrical Idle to valid differential output	_	_	_	8	ns
L _{TX-SKEW}	Lane-to-lane output skew	_	_	—		ps

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3.26. CPRI LV2 E.48 Electrical and Timing Characteristics – Preliminary

Symbol	Description	Test Conditions	Min	Тур	Max	Unit
Transmit	-					
UI	Unit Interval	-	203.43	203.45	203.47	ps
T _{DCD}	Duty Cycle Distortion	-	-	—	0.05	UI
J _{UBHPJ}	Uncorrelated Bounded High Probability Jitter	_	_	_	0.15	UI
J _{TOTAL}	Total Jitter	-	-	_	0.3	UI
Z _{RX-DIFF-DC}	DC differential Impedance	-	80	-	120	Ω
T _{SKEW}	Skew between differential signals	_	_	—	9	ps
Ty Differential Return Loss (\$22)		100 MHz < freq < 3.6864 GHz	_	-	-8	dB
R _{LTX-DIFF}	including package and silicon	3.6864 GHz < freq < 4.9152 GHz	Ι	_	-8 + 16.6 *log (freq/3.6864)	dB
R _{LTX-CM}	Tx Common Mode Return Loss, including package and silicon	100 MHz < freq < 3.6864 GHz	6	-	-	dB
I _{TX-SHORT}	Transmitter short-circuit current	-	_	_	100	mA
T _{RISE_FALL-DIFF}	Differential Rise and Fall Time	-		—	_	ps
L _{TX-SKEW}	Lane-to-lane output skew	-	_	—		ps
Receive		·				
UI	Unit Interval	—	203.43	203.45	203.47	ps
V _{RX-DIFF-PP}	Differential Rx peak-peak voltage	-	_	_	1.2	V, p-p
V _{RX-EYE_Y1_Y2}	Receiver eye opening mask, Y1 and Y2	_	62.5	-	375	mV, diff
V _{RX-EYE_X1}	Receiver eye opening mask, X1	-	-	_	0.3	UI
T _{RX-TJ}	Receiver total jitter tolerance (not including sinusoidal)	_	_	_	0.6	UI
_	Receiver differential Return Loss,	100 MHz < freq < 3.6864 GHz	_	-	-8	dB
R _{LRX-DIFF}	package plus silicon	3.6864 GHz < freq < 4.9152 GHz	_	-	-8 + 16.6 *log (freq/3.6864)	dB
R _{LRX-CM}	Receiver common mode Return Loss, package plus silicon	_	6	_	_	dB
Z _{RX-DIFF-DC}	Receiver DC differential impedance	_	80	100	120	Ω

Table 3.32. CPRI LV2 E.48 Electrical and Timing Characteristics

Note: Data is measured with PRBS7 data pattern, not with PRBS-31 pattern.

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3.31. sysCONFIG Port Timing Specifications

Over recommended operating conditions.

Table 3.42. ECP5/ECP5-5G sysCONFIG Port Timing Specifications

Symbol	Parameter		Min	Max	Unit
POR, Confi	guration Initialization, and Wakeup	I	1	1	1
t _{ICFG}	Time from the Application of $V_{CC, V}$ V _{CCAUX} or V _{CCI08} (whichever is the last) to the rising edge of INITN	-	_	33	ms
t _{VMC}	Time from t_{ICFG} to the valid Master CCLK	_	_	5	us
t _{cz}	CCLK from Active to High-Z	_	_	300	ns
Master CCI	LK	T	1	1	1
f _{MCLK}	Frequency	All selected frequencies	-20	20	%
t _{MCLK-DC}	Duty Cycle	All selected frequencies	40	60	%
All Configu	ration Modes				
t _{PRGM}	PROGRAMN LOW pulse accepted	_	110	_	ns
t _{PRGMRJ}	PROGRAMN LOW pulse rejected	_	_	50	ns
t _{INITL}	INITN LOW time	_	_	55	ns
t _{dppint}	PROGRAMN LOW to INITN LOW	_	_	70	ns
t _{DPPDONE}	PROGRAMN LOW to DONE LOW	_	_	80	ns
t _{IODISS}	PROGRAMN LOW to I/O Disabled	_	_	150	ns
Slave SPI		T	1		1
f _{CCLK}	CCLK input clock frequency	_	_	60	MHz
t _{CCLKH}	CCLK input clock pulsewidth HIGH	_	6	_	ns
t _{cclkl}	CCLK input clock pulsewidth LOW	_	6	_	ns
t _{stsu}	CCLK setup time	_	1	_	ns
t _{sth}	CCLK hold time	_	1	_	ns
t _{sтсо}	CCLK falling edge to valid output	_	_	10	ns
t _{stoz}	CCLK falling edge to valid disable	-	_	10	ns
t _{stov}	CCLK falling edge to valid enable	_	_	10	ns
t _{scs}	Chip Select HIGH time	-	25	_	ns
t _{scss}	Chip Select setup time	_	3	_	ns
t _{scsн}	Chip Select hold time	_	3	_	ns
Master SPI		,	,		
f _{CCLK}	Max selected CCLK output frequency	_	_	62	MHz
t _{cclкн}	CCLK output clock pulse width HIGH	_	3.5	_	ns
t _{CCLKL}	CCLK output clock pulse width LOW	_	3.5	_	ns
t _{stsu}	CCLK setup time	_	5	_	ns
t _{sтн}	CCLK hold time	_	1	_	ns
t _{CSSPI}	INITN HIGH to Chip Select LOW	_	100	200	ns
t _{CFGX}	INITN HIGH to first CCLK edge	_	_	150	ns
Slave Seria	I				
f _{cclk}	CCLK input clock frequency	_	_	66	MHz
t _{ssch}	CCLK input clock pulse width HIGH	_	5	-	ns
t _{sscl}	CCLK input clock pulse width LOW	—	5	-	ns
t _{suscdi}	CCLK setup time	_	0.5	_	ns
t _{HSCDI}	CCLK hold time	_	1.5	_	ns

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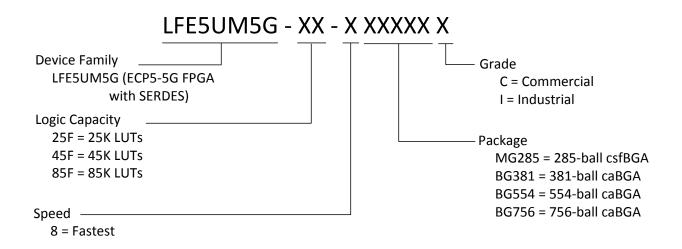
4. Pinout Information

4.1. Signal Descriptions

Signal Name		Description
General Purpose		
P[L/R] [Group Number]_[A/B/C/D]	ı/o	 [L/R] indicates the L (Left), or R (Right) edge of the device. [Group Number] indicates the PIO [A/B/C/D] group. [A/B/C/D] indicates the PIO within the PIC to which the pad is connected. Some of these user-programmable pins are shared with special function pins. These pins, when not used as special purpose pins, can be programmed as I/Os for user logic. During configuration the user-programmable I/Os are tristated with an internal pull-down resistor enabled. If any pin is not used (or not bonded to a package pin), it is tristated and default to have pull-down enabled after configuration. PIO A and B are grouped as a pair, and PIO C and D are group as a pair. Each pair supports true LVDS differential input buffer. Only PIO A and B pair supports true LVDS differential output buffer. Each A/B and C/D pair supports programmable on/off differential input termination of 100 Ω.
P[T/B][Group Number]_[A/B]	1/0	[T/B] indicates the T (top) or B (bottom) edge of the device. [Group Number] indicates the PIO [A/B] group. [A/B] indicates the PIO within the PIC to which the pad is connected. Some of these user-programmable pins are shared with sysConfig pins. These pins, when not used as configuration pins, can be programmed as I/Os for user logic. During configuration, the pins not used in configuration are tristated with an internal pull-down resistor enabled. If any pin is not used (or not bonded to a package pin), it is tristated and default to have pull-down enabled after configuration. PIOs on top and bottom do not support differential input signaling or true LVDS output signaling, but it can support emulated differential output buffer. PIO A/B forms a pair of emulated differential output buffer.
GSRN	1	Global RESET signal (active low). Any I/O pin can be GSRN.
NC	_	No connect.
RESERVED	_	This pin is reserved and should not be connected to anything on the board.
GND	_	Ground. Dedicated pins.
V _{cc}	-	Power supply pins for core logic. Dedicated pins. V _{CC} = 1.1 V (ECP5), 1.2 V (ECP5UM5G)
V _{CCAUX}	_	Auxiliary power supply pin. This dedicated pin powers all the differential and referenced input buffers. $V_{CCAUX} = 2.5 V$.
V _{CCIOx}	_	Dedicated power supply pins for I/O bank x. V_{CCIO8} is used for configuration and JTAG.
VREF1_x	_	Reference supply pins for I/O bank x. Pre-determined shared pin in each bank are assigned as VREF1 input. When not used, they may be used as I/O pins.
PLL, DLL and Clock Functions		
[LOC][_GPLL[T, C]_IN	I	General Purpose PLL (GPLL) input pads: [LOC] = ULC, LLC, URC and LRC, T = true and C = complement. These pins are shared I/O pins. When not configured as GPLL input pads, they can be used as general purpose I/O pins.
GR_PCLK[Bank][num]	I	General Routing Signals in Banks 0, 1, 2, 3, 4, 6 and 7. There are two in each bank ([num] = 0, 1). Refer to ECP5 sysClock PLL/DLL Design and Usage Guide (TN1263). These pins are shared I/O pins. When not configured as GR pins, they can be used as general purpose I/O pins.
PCLK[T/C][Bank]_[num]	I/O	General Purpose Primary CLK pads: [T/C] = True/Complement, [Bank] = (0, 1, 2, 3, 6 and 7). There are two in each bank ([num] = 0, 1). These are shared I/ O pins. When not configured as PCLK pins, they can be used as general purpose I/O pins.

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5.2. Ordering Part Numbers

5.2.1. Commercial

Part number	Grade	Package	Pins	Temp.	LUTs (K)	SERDES
LFE5U-12F-6BG256C	-6	Lead free caBGA	256	Commercial	12	No
LFE5U-12F-7BG256C	-7	Lead free caBGA	256	Commercial	12	No
LFE5U-12F-8BG256C	-8	Lead free caBGA	256	Commercial	12	No
LFE5U-12F-6MG285C	-6	Lead free csfBGA	285	Commercial	12	No
LFE5U-12F-7MG285C	-7	Lead free csfBGA	285	Commercial	12	No
LFE5U-12F-8MG285C	-8	Lead free csfBGA	285	Commercial	12	No
LFE5U-12F-6BG381C	-6	Lead free caBGA	381	Commercial	12	No
LFE5U-12F-7BG381C	-7	Lead free caBGA	381	Commercial	12	No
LFE5U-12F-8BG381C	-8	Lead free caBGA	381	Commercial	12	No
LFE5U-25F-6BG256C	-6	Lead free caBGA	256	Commercial	24	No
LFE5U-25F-7BG256C	-7	Lead free caBGA	256	Commercial	24	No
LFE5U-25F-8BG256C	-8	Lead free caBGA	256	Commercial	24	No
LFE5U-25F-6MG285C	-6	Lead free csfBGA	285	Commercial	24	No
LFE5U-25F-7MG285C	-7	Lead free csfBGA	285	Commercial	24	No
LFE5U-25F-8MG285C	-8	Lead free csfBGA	285	Commercial	24	No
LFE5U-25F-6BG381C	-6	Lead free caBGA	381	Commercial	24	No
LFE5U-25F-7BG381C	-7	Lead free caBGA	381	Commercial	24	No
LFE5U-25F-8BG381C	-8	Lead free caBGA	381	Commercial	24	No
LFE5U-45F-6BG256C	-6	Lead free caBGA	256	Commercial	44	No
LFE5U-45F-7BG256C	-7	Lead free caBGA	256	Commercial	44	No
LFE5U-45F-8BG256C	-8	Lead free caBGA	256	Commercial	44	No
LFE5U-45F-6MG285C	-6	Lead free csfBGA	285	Commercial	44	No
LFE5U-45F-7MG285C	-7	Lead free csfBGA	285	Commercial	44	No
LFE5U-45F-8MG285C	-8	Lead free csfBGA	285	Commercial	44	No
LFE5U-45F-6BG381C	-6	Lead free caBGA	381	Commercial	44	No
LFE5U-45F-7BG381C	-7	Lead free caBGA	381	Commercial	44	No
LFE5U-45F-8BG381C	-8	Lead free caBGA	381	Commercial	44	No
LFE5U-45F-6BG554C	-6	Lead free caBGA	554	Commercial	44	No
LFE5U-45F-7BG554C	-7	Lead free caBGA	554	Commercial	44	No

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Supplemental Information

For Further Information

A variety of technical notes for the ECP5/ECP5-5G family are available.

- High-Speed PCB Design Considerations (TN1033)
- Transmission of High-Speed Serial Signals Over Common Cable Media (TN1066)
- PCB Layout Recommendations for BGA Packages (TN1074)
- Minimizing System Interruption During Configuration Using TransFR Technology (TN1087)
- Electrical Recommendations for Lattice SERDES (FPGA-TN-02077)
- LatticeECP3, ECP-5 and ECP5-5G Soft Error Detection (SED)/Correction (SEC) Usage Guide (TN1184)
- Using TraceID (TN1207)
- Sub-LVDS Signaling Using Lattice Devices (TN1210)
- Advanced Security Encryption Key Programming Guide for ECP5, ECP5-5G, LatticeECP3, and LatticeECP2/MS Devices (TN1215)
- LatticeECP3, LatticeECP2/M, ECP5 and ECP5-5G Dual Boot and Multiple Boot Feature (TN1216)
- ECP5 and ECP5-5G sysCONFIG Usage Guide (TN1260)
- ECP5 and ECP5-5G SERDES/PCS Usage Guide (TN1261)
- ECP5 and ECP5-5G sysIO Usage Guide (TN1262)
- ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide (TN1263)
- ECP5 and ECP5-5G Memory Usage Guide (TN1264)
- ECP5 and ECP5-5G High-Speed I/O Interface (TN1265)
- Power Consumption and Management for ECP5 and ECP5-5G Devices (TN1266)
- ECP5 and ECP5-5G sysDSP Usage Guide (TN1267)
- ECP5 and ECP5-5G Hardware Checklist (FPGA-TN-02038)
- Solder Reflow Guide for Surface Mount Devices (FPGA-TN-02041)
- ECP5 and ECP5-5G PCI Express Soft IP Ease of Use Guidelines (FPGA-TN-02045)
- Programming External SPI Flash through JTAG for ECP5/ECP5-5G (FPGA-TN-02050)
- Adding Scalable Power and Thermal Management to ECP5 Using L-ASC10 (AN6095)

For further information on interface standards refer to the following websites:

- JEDEC Standards (LVTTL, LVCMOS, SSTL): www.jedec.org
- PCI: www.pcisig.com